

**Notice of References Cited**

Application/Control No.

10/579,158

Applicant(s)/Patent Under  
Reexamination  
DEES, WALTER

Examiner

Ashraf Zahr

Art Unit

2179

Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,889,516 A	03-1999	Hickey et al.	715/740
*	B	US-5,949,412 A	09-1999	Huntsman, Robert A.	715/740
*	C	US-6,020,881 A	02-2000	Naughton et al.	715/740
*	D	US-2001/0009424 A1	07-2001	Sekiguchi, Kiyonori	345/740
*	E	US-6,313,851 B1	11-2001	Matthews et al.	715/718
*	F	US-2002/0051012 A1	05-2002	Gomes et al.	345/740
*	G	US-2002/0154161 A1	10-2002	Friedman et al.	345/740
*	H	US-6,507,351 B1	01-2003	Bixler, Donald Brinton	715/810
*	I	US-6,538,668 B1	03-2003	Ruberg et al.	715/747
*	J	US-6,597,374 B1	07-2003	Baker et al.	715/717
*	K	US-2003/0234809 A1	12-2003	Parker et al.	345/740
*	L	US-6,674,450 B1	01-2004	Toub et al.	715/749
*	M	US-6,680,730 B1	01-2004	Shields et al.	345/169

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**

Application/Control No.

10/579,158

Applicant(s)/Patent Under  
Reexamination  
DEES, WALTER

Examiner

Ashraf Zahr

Art Unit

2179

Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,745,252 B1	06-2004	Yanagawa et al.	710/8
*	B	US-6,785,579 B2	08-2004	Huang et al.	700/65
*	C	US-6,844,886 B1	01-2005	Yanagawa et al.	715/744
*	D	US-6,870,555 B2	03-2005	Sekiguchi, Kiyonori	715/740
*	E	US-7,027,881 B2	04-2006	Yumoto et al.	700/65
*	F	US-7,240,289 B2	07-2007	Naughton et al.	715/740
*	G	US-7,243,151 B2	07-2007	Sekiguchi, Kiyonori	709/227
*	H	US-7,293,236 B2	11-2007	Choi et al.	715/734
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.